

Efficient at-speed interconnect BIST and diagnosis framework

Jutman, Artur Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005 2005 / p. 257-258
: ill https://artiklid.elnet.ee/record=b1018804*est

Evolutionary approach to test generation for functional BIST

Skobtsov, Y.A.; Ivanov, D.E.; Skobtsov, V.Y.; **Ubar, Raimund-Johannes**; **Raik, Jaan** Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005 2005 / p. 151-155 : ill https://artiklid.elnet.ee/record=b1018764*est

Foreword

Ubar, Raimund-Johannes; Prinetto, Paolo; Al-Hashimi, Bashir Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005 2005 / p. III